











CSD19502Q5B

SLPS413B - DECEMBER 2013 - REVISED MAY 2017

CSD19502Q5B 80 V N-Channel NexFET™ Power MOSFET

Features

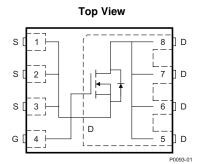
- Ultra-Low Q_a and Q_{ad}
- Low Thermal Resistance
- Avalanche Rated
- Logic Level
- Pb-Free Terminal Plating
- **RoHS Compliant**
- Halogen Free
- SON 5-mm × 6-mm Plastic Package

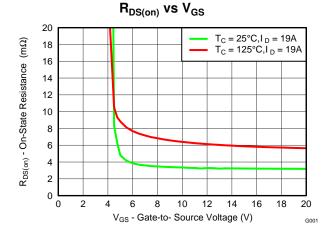
Applications

- Secondary Side Synchronous Rectifier
- Motor Control

Description

This 3.4 m Ω , 80 V, SON 5 mm × 6 mm NexFETTM power MOSFET is designed to minimize losses in power conversion applications.





Product Summary

$T_A = 25^\circ$	С	TYPICAL VA	UNIT		
V_{DS}	Drain-to-Source Voltage	80	٧		
Q_g	Gate Charge Total (10 V)	48		nC	
Q_{gd}	Gate Charge Gate to Drain 8.6				
R _{DS(on)}	Drain-to-Source On Resistance	$V_{GS} = 6 V$	3.8	mΩ	
	Diam-to-Source On nesistance	V _{GS} = 10 V 3.4		mΩ	
$V_{GS(th)}$	Threshold Voltage	2.7	V		

Ordering Information⁽¹⁾

Device	Media	Qty	Package	Ship
CSD19502Q5B	13-Inch Reel	2500	SON 5 x 6 mm	Tape and
CSD19502Q5BT	13-Inch Reel	250	Plastic Package	Reel

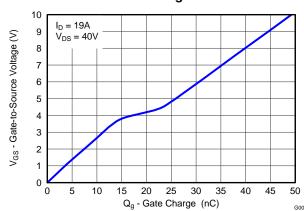
(1) For all available packages, see the orderable addendum at the end of the data sheet.

Absolute Maximum Ratings

T _A = 2	5°C	VALUE	UNIT
V_{DS}	Drain-to-Source Voltage	80	٧
V_{GS}	Gate-to-Source Voltage	±20	V
	Continuous Drain Current (Package limited)	100	
I _D	Continuous Drain Current (Silicon limited), $T_C = 25^{\circ}C$	157 A	
	Continuous Drain Current ⁽¹⁾	17	
I _{DM}	Pulsed Drain Current ⁽²⁾	400	Α
D	Power Dissipation ⁽¹⁾	3.1	W
P_D	Power Dissipation, T _C = 25°C	195	VV
T _J , T _{stg}	Operating Junction and Storage Temperature Range	-55 to 150	ô
E _{AS}	Avalanche Energy, single pulse I_D = 74 A, L = 0.1 mH, R_G = 25 Ω	274	mJ

- (1) Typical $R_{\rm 0JA} = 40^{\circ} \rm C/W$ on a 1-inch², 2-oz. Cu pad on a 0.06-inch thick FR4 PCB.
- (2) Max $R_{\theta JC} = 0.8$ °C/W, pulse duration $\leq 100 \mu s$, duty cycle $\leq 1\%$

Gate Charge





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4 Revision History

C	changes from Revision A (June 2014) to Revision B	Page
•	Added the Receiving Notification of Documentation Updates and Community Resources sections to Device and Documentation Support.	7
•	Changed the dimension between pads 3 and 4 from 0.028 inches: to 0.050 inches in the <i>Recommended PCB Pattern</i> section diagram	
C	changes from Original (December 2013) to Revision A	Page
•	Added small reel option to ordering information table.	1

Increased silicon limit for continuous drain current to 157 A.
Increased max pulsed current to 400 A.
Added max power rating when the case temperature is held to 25°C.
Updated pulsed current conditions to specify duty cycle ≤ 1%, pulse duration ≤ 100 μs, and Max R_{θJC} = 0.8°C/W.
Updated Figure 10.
Updated mechanical drawing.

Product Folder Links: CSD19502Q5B

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5 Specifications

5.1 Electrical Characteristics

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC	CHARACTERISTICS		<u>'</u>		•	
BV _{DSS}	Drain-to-Source Voltage	V _{GS} = 0 V, I _D = 250 μA	80			V
I _{DSS}	Drain-to-Source Leakage Current	V _{GS} = 0 V, V _{DS} = 64 V			1	μА
I _{GSS}	Gate-to-Source Leakage Current	V _{DS} = 0 V, V _{GS} = 20 V			100	nA
V _{GS(th)}	Gate-to-Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.2	2.7	3.3	V
	Duein to Course On Besistance	V _{GS} = 6 V, I _D = 19 A		3.8	4.8	mΩ
R _{DS(on)} Drain-to-Source On Resistance		V _{GS} = 10 V, I _D = 19 A		3.4	4.1	mΩ
9 _{fs}	Transconductance	V _{DS} = 8 V, I _D = 19 A		88		S
DYNAMI	IC CHARACTERISTICS		•			
C _{iss}	Input Capacitance		3	3750	4870	pF
C _{oss}	Output Capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 40 \text{ V}, f = 1 \text{ MHz}$		925	1202	pF
C _{rss}	Reverse Transfer Capacitance			17	22	pF
R _G	Series Gate Resistance			1.2	2.4	Ω
Qg	Gate Charge Total (10 V)			48	62	nC
Q _{gd}	Gate Charge Gate to Drain	V 40 V 1 40 A		8.6		nC
Q _{gs}	Gate Charge Gate to Source	$V_{DS} = 40 \text{ V}, I_{D} = 19 \text{ A}$		14		nC
Q _{g(th)}	Gate Charge at V _{th}			10		nC
Q _{oss}	Output Charge	V _{DS} = 40 V, V _{GS} = 0 V		130		nC
t _{d(on)}	Turn On Delay Time			8		ns
t _r	Rise Time	V _{DS} = 40 V, V _{GS} = 10 V,		6		ns
t _{d(off)}	Turn Off Delay Time	$I_{DS} = 19 \text{ A}, R_G = 0 \Omega$		22		ns
t _f	Fall Time			7		ns
DIODE O	CHARACTERISTICS				·	
V_{SD}	Diode Forward Voltage	I _{SD} = 19 A, V _{GS} = 0 V		0.8	1	V
Q _{rr}	Reverse Recovery Charge	V _{DS} = 40 V, I _F = 19 A,		275		nC
t _{rr}	Reverse Recovery Time	di/dt = 300 A/μs		72		ns

5.2 Thermal Information

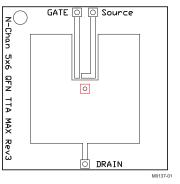
(T_A = 25°C unless otherwise stated)

	THERMAL METRIC	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance ⁽¹⁾			8.0	°C/W
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance (1)(2)			50	-C/VV

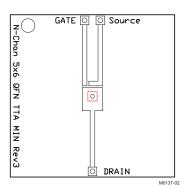
 ⁽¹⁾ R_{θJC} is determined with the device mounted on a 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu pad on a 1.5-inches × 1.5-inches (3.81-cm × 3.81-cm), 0.06-inch (1.52-mm) thick FR4 PCB. R_{θJC} is specified by design, whereas R_{θJA} is determined by the user's board design.
(2) Device mounted on FR4 material with 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu.

Product Folder Links: CSD19502Q5B





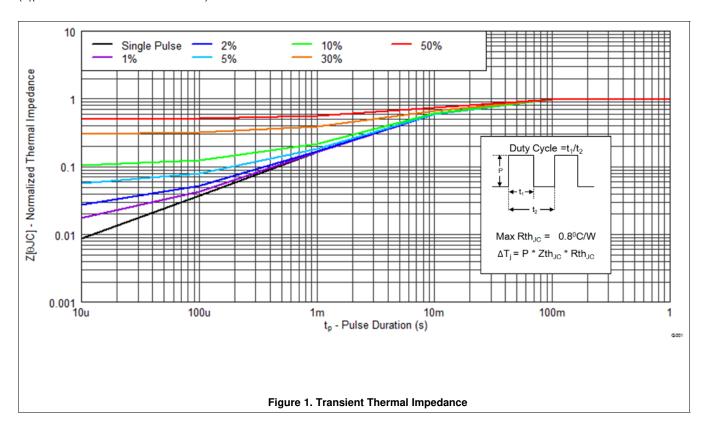
Max $R_{\theta JA} = 50^{\circ} C/W$ when mounted on 1 inch² (6.45 cm²) of 2-oz. (0.071-mm thick) Cu.



Max $R_{\theta JA} = 125^{\circ} C/W$ when mounted on a minimum pad area of 2-oz. (0.071-mm thick) Cu.

5.3 Typical MOSFET Characteristics

(T_A = 25°C unless otherwise stated)



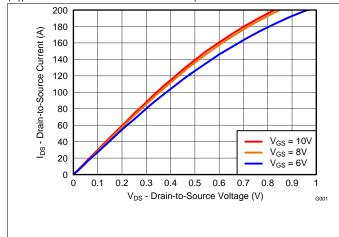
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Typical MOSFET Characteristics (continued)

(T_A = 25°C unless otherwise stated)



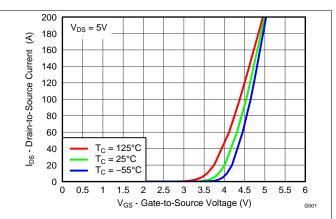


Figure 2. Saturation Characteristics

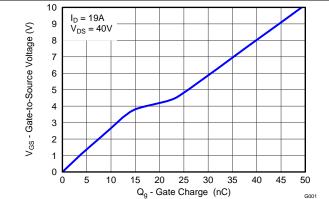


Figure 3. Transfer Characteristics

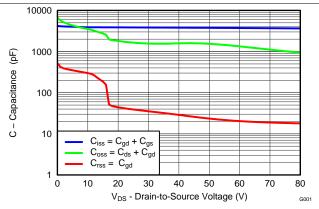


Figure 4. Gate Charge

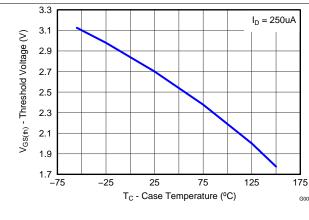


Figure 5. Capacitance

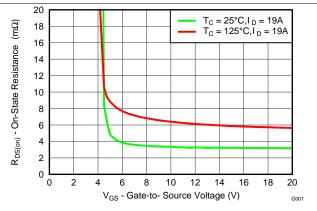


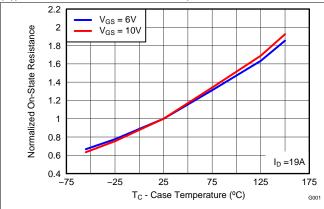
Figure 6. Threshold Voltage vs Temperature

Figure 7. On-State Resistance vs Gate-to-Source Voltage



Typical MOSFET Characteristics (continued)

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$



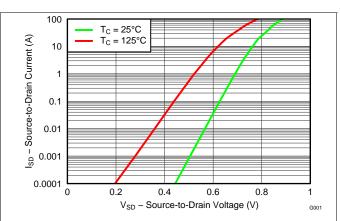
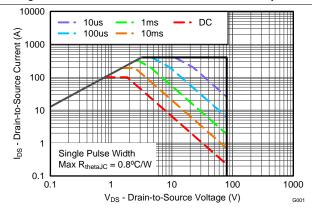


Figure 8. Normalized On-State Resistance vs Temperature





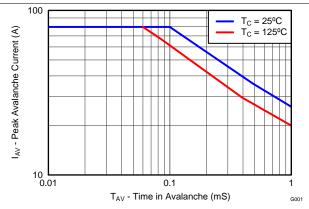


Figure 10. Maximum Safe Operating Area



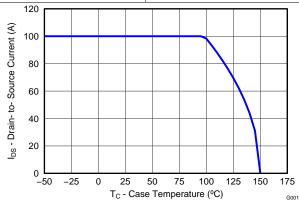


Figure 12. Maximum Drain Current vs Temperature

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6 Device and Documentation Support

6.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

6.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

6.3 Trademarks

NexFET, E2E are trademarks of Texas Instruments.

6.4 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

6.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

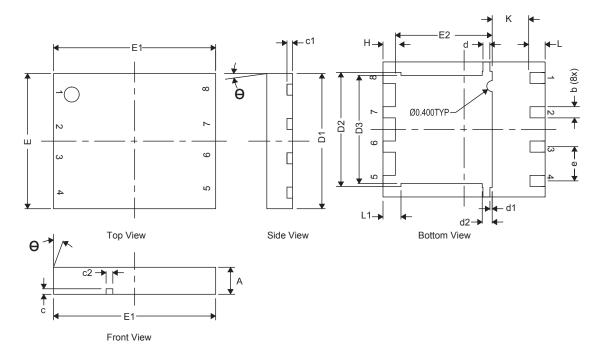
Product Folder Links: CSD19502Q5B



7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

7.1 Q5B Package Dimensions



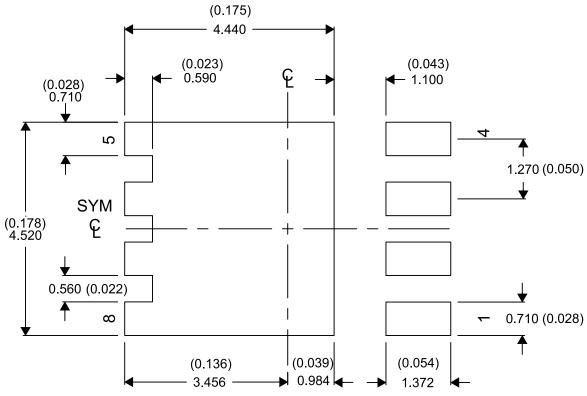
DIM	MILLIMETERS							
DIIVI	MIN	NOM	MAX					
Α	0.80	1.00	1.05					
b	0.36	0.41	0.46					
С	0.15	0.20	0.25					
c1	0.15	0.20	0.25					
c2	0.20	0.25	0.30					
D1	4.90	5.00	5.10					
D2	4.12	4.22	4.32					
D3	3.90	4.00	4.10					
d	0.20	0.25	0.30					
d1		0.085 TYP						
d2	0.319	0.369	0.419					
E	4.90	5.00	5.10					
E1	5.90	6.00	6.10					
E2	3.48	3.58	3.68					
е		1.27 TYP						
Н	0.36	0.46	0.56					
L	0.46	0.56	0.66					
L1	0.57	0.67	0.77					
θ	0°		_					
K		1.40 TYP	·					

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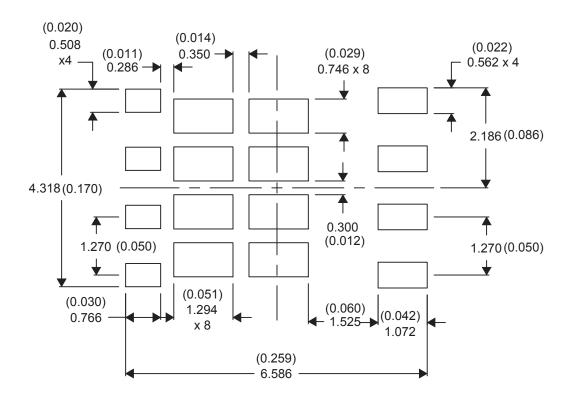


7.2 Recommended PCB Pattern



For recommended circuit layout for PCB designs, see application note SLPA005 – Reducing Ringing Through PCB Layout Techniques.

7.3 Recommended Stencil Pattern

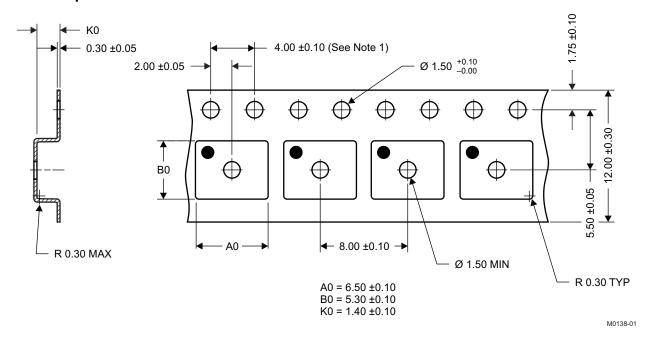


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7.4 Q5B Tape and Reel Information



Notes:

- 1. 10-sprocket hole-pitch cumulative tolerance ±0.2
- 2. Camber not to exceed 1 mm in 100 mm, noncumulative over 250 mm
- 3. Material: black static-dissipative polystyrene
- 4. All dimensions are in mm (unless otherwise specified).
- 5. A0 and B0 measured on a plane 0.3 mm above the bottom of the pocket.

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PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CSD19502Q5B	ACTIVE	VSON-CLIP	DNK	8	2500	RoHS-Exempt & Green	SN	Level-1-260C-UNLIM	-55 to 150	CSD19502	Samples
CSD19502Q5BT	ACTIVE	VSON-CLIP	DNK	8	250	RoHS-Exempt & Green	SN	Level-1-260C-UNLIM	-55 to 150	CSD19502	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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